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"[Embedded - Microcontrollers](#)" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "[Embedded - Microcontrollers](#)"

Details

Product Status	Active
Core Processor	ARM® Cortex®-M0
Core Size	32-Bit Single-Core
Speed	48MHz
Connectivity	CANbus, I ² C, IrDA, LINbus, SPI, UART/USART
Peripherals	DMA, I ² S, POR, PWM, WDT
Number of I/O	37
Program Memory Size	256KB (256K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	32K x 8
Voltage - Supply (Vcc/Vdd)	1.65V ~ 3.6V
Data Converters	A/D 13x12b; D/A 2x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	48-UFQFN Exposed Pad
Supplier Device Package	48-UFQFPN (7x7)
Purchase URL	https://www.e-xfl.com/product-detail/stmicroelectronics/stm32f098ccu6

2 Description

The STM32F098CC/RC/VC microcontrollers incorporate the high-performance ARM® Cortex®-M0 32-bit RISC core operating at up to 48 MHz frequency, high-speed embedded memories (256 Kbytes of Flash memory and 32 Kbytes of SRAM), and an extensive range of enhanced peripherals and I/Os. The device offers standard communication interfaces (two I²Cs, two SPIs/one I²S, one HDMI CEC and up to eight USARTs), one CAN, one 12-bit ADC, one 12-bit DAC with two channels, seven 16-bit timers, one 32-bit timer and an advanced-control PWM timer.

The STM32F098CC/RC/VC microcontrollers operate in the -40 to +85 °C and -40 to +105 °C temperature ranges, at a 1.8 V ± 8% power supply. A comprehensive set of power-saving modes allows the design of low-power applications.

The STM32F098CC/RC/VC microcontrollers include devices in seven different package ranging from 48 pins to 100 pins with a die form also available upon request. Depending on the device chosen, different sets of peripherals are included.

These features make the STM32F098CC/RC/VC microcontrollers suitable for a wide range of applications such as application control and user interfaces, hand-held equipment, A/V receivers and digital TV, PC peripherals, gaming and GPS platforms, industrial applications, PLCs, inverters, printers, scanners, alarm systems, video intercoms and HVACs.

3 Functional overview

Figure 1 shows the general block diagram of the STM32F098CC/RC/VC devices.

3.1 ARM[®]-Cortex[®]-M0 core

The ARM[®] Cortex[®]-M0 is a generation of ARM 32-bit RISC processors for embedded systems. It has been developed to provide a low-cost platform that meets the needs of MCU implementation, with a reduced pin count and low-power consumption, while delivering outstanding computational performance and an advanced system response to interrupts.

The ARM[®] Cortex[®]-M0 processors feature exceptional code-efficiency, delivering the high performance expected from an ARM core, with memory sizes usually associated with 8- and 16-bit devices.

The STM32F098CC/RC/VC devices embed ARM core and are compatible with all ARM tools and software.

3.2 Memories

The device has the following features:

- 32 Kbytes of embedded SRAM accessed (read/write) at CPU clock speed with 0 wait states and featuring embedded parity checking with exception generation for fail-critical applications.
- The non-volatile memory is divided into two arrays:
 - 256 Kbytes of embedded Flash memory for programs and data
 - Option bytes

The option bytes are used to write-protect the memory (with 4 KB granularity) and/or readout-protect the whole memory with the following options:

- Level 0: no readout protection
- Level 1: memory readout protection, the Flash memory cannot be read from or written to if either debug features are connected or boot in RAM is selected
- Level 2: chip readout protection, debug features (Cortex[®]-M0 serial wire) and boot in RAM selection disabled

3.3 Boot modes

At startup, the boot pin and boot selector option bits are used to select one of the three boot options:

- boot from User Flash memory
- boot from System Memory
- boot from embedded SRAM

The boot pin is shared with the standard GPIO and can be disabled through the boot selector option bits. The boot loader is located in System Memory. It is used to reprogram the Flash memory by using USART on pins PA14/PA15 or PA9/PA10 or I²C on pins PB6/PB7.

3.10.3 V_{BAT} battery voltage monitoring

This embedded hardware feature allows the application to measure the V_{BAT} battery voltage using the internal ADC channel ADC_IN18. As the V_{BAT} voltage may be higher than V_{DDA} , and thus outside the ADC input range, the V_{BAT} pin is internally connected to a bridge divider by 2. As a consequence, the converted digital value is half the V_{BAT} voltage.

3.11 Digital-to-analog converter (DAC)

The two 12-bit buffered DAC channels can be used to convert digital signals into analog voltage signal outputs. The chosen design structure is composed of integrated resistor strings and an amplifier in non-inverting configuration.

This digital Interface supports the following features:

- 8-bit or 12-bit monotonic output
- Left or right data alignment in 12-bit mode
- Synchronized update capability
- Noise-wave generation
- Triangular-wave generation
- Dual DAC channel independent or simultaneous conversions
- DMA capability for each channel
- External triggers for conversion

Six DAC trigger inputs are used in the device. The DAC is triggered through the timer trigger outputs and the DAC interface is generating its own DMA requests.

3.12 Comparators (COMP)

The device embeds two fast rail-to-rail low-power comparators with programmable reference voltage (internal or external), hysteresis and speed (low speed for low power) and with selectable output polarity.

The reference voltage can be one of the following:

- External I/O
- DAC output pins
- Internal reference voltage or submultiple (1/4, 1/2, 3/4). Refer to [Table 25: Embedded internal reference voltage](#) for the value and precision of the internal reference voltage.

Both comparators can wake up from STOP mode, generate interrupts and breaks for the timers and can be also combined into a window comparator.

3.13 Touch sensing controller (TSC)

The STM32F098CC/RC/VC devices provide a simple solution for adding capacitive sensing functionality to any application. These devices offer up to 23 capacitive sensing channels distributed over 8 analog I/O groups.

Capacitive sensing technology is able to detect the presence of a finger near a sensor which is protected from direct touch by a dielectric (glass, plastic...). The capacitive variation

introduced by the finger (or any conductive object) is measured using a proven implementation based on a surface charge transfer acquisition principle. It consists in charging the sensor capacitance and then transferring a part of the accumulated charges into a sampling capacitor until the voltage across this capacitor has reached a specific threshold. To limit the CPU bandwidth usage, this acquisition is directly managed by the hardware touch sensing controller and only requires few external components to operate. For operation, one capacitive sensing GPIO in each group is connected to an external capacitor and cannot be used as effective touch sensing channel.

The touch sensing controller is fully supported by the STMTouch touch sensing firmware library, which is free to use and allows touch sensing functionality to be implemented reliably in the end application.

Table 4. Capacitive sensing GPIOs available on STM32F098CC/RC/VC devices

Group	Capacitive sensing signal name	Pin name	Group	Capacitive sensing signal name	Pin name
1	TSC_G1_IO1	PA0	5	TSC_G5_IO1	PB3
	TSC_G1_IO2	PA1		TSC_G5_IO2	PB4
	TSC_G1_IO3	PA2		TSC_G5_IO3	PB6
	TSC_G1_IO4	PA3		TSC_G5_IO4	PB7
2	TSC_G2_IO1	PA4	6	TSC_G6_IO1	PB11
	TSC_G2_IO2	PA5		TSC_G6_IO2	PB12
	TSC_G2_IO3	PA6		TSC_G6_IO3	PB13
	TSC_G2_IO4	PA7		TSC_G6_IO4	PB14
3	TSC_G3_IO1	PC5	7	TSC_G7_IO1	PE2
	TSC_G3_IO2	PB0		TSC_G7_IO2	PE3
	TSC_G3_IO3	PB1		TSC_G7_IO3	PE4
4	TSC_G4_IO1	PA9		TSC_G7_IO4	PE5
	TSC_G4_IO2	PA10	8	TSC_G8_IO1	PD12
	TSC_G4_IO3	PA11		TSC_G8_IO2	PD13
	TSC_G4_IO4	PA12		TSC_G8_IO3	PD14
				TSC_G8_IO4	PD15

Table 5. Number of capacitive sensing channels available on STM32F098CC/RC/VC devices

Analog I/O group	Number of capacitive sensing channels		
	STM32F098Vx	STM32F098Rx	STM32F098Cx
G1	3	3	3
G2	3	3	3
G3	2	2	1
G4	3	3	3

Table 5. Number of capacitive sensing channels available on STM32F098CC/RC/VC devices (continued)

Analog I/O group	Number of capacitive sensing channels		
	STM32F098Vx	STM32F098Rx	STM32F098Cx
G5	3	3	3
G6	3	3	3
G7	3	0	0
G8	3	0	0
Number of capacitive sensing channels	23	17	16

3.14 Timers and watchdogs

The STM32F098CC/RC/VC devices include up to six general-purpose timers, two basic timers and an advanced control timer.

[Table 6](#) compares the features of the different timers.

Table 6. Timer feature comparison

Timer type	Timer	Counter resolution	Counter type	Prescaler factor	DMA request generation	Capture/compare channels	Complementary outputs
Advanced control	TIM1	16-bit	Up, down, up/down	integer from 1 to 65536	Yes	4	3
General purpose	TIM2	32-bit	Up, down, up/down	integer from 1 to 65536	Yes	4	-
	TIM3	16-bit	Up, down, up/down	integer from 1 to 65536	Yes	4	-
	TIM14	16-bit	Up	integer from 1 to 65536	No	1	-
	TIM15	16-bit	Up	integer from 1 to 65536	Yes	2	1
	TIM16 TIM17	16-bit	Up	integer from 1 to 65536	Yes	1	1
Basic	TIM6 TIM7	16-bit	Up	integer from 1 to 65536	Yes	-	-

3.14.1 Advanced-control timer (TIM1)

The advanced-control timer (TIM1) can be seen as a three-phase PWM multiplexed on six channels. It has complementary PWM outputs with programmable inserted dead times. It

3.19 High-definition multimedia interface (HDMI) - consumer electronics control (CEC)

The device embeds a HDMI-CEC controller that provides hardware support for the Consumer Electronics Control (CEC) protocol (Supplement 1 to the HDMI standard).

This protocol provides high-level control functions between all audiovisual products in an environment. It is specified to operate at low speeds with minimum processing and memory overhead. It has a clock domain independent from the CPU clock, allowing the HDMI_CEC controller to wakeup the MCU from Stop mode on data reception.

3.20 Controller area network (CAN)

The CAN is compliant with specifications 2.0A and B (active) with a bit rate up to 1 Mbit/s. It can receive and transmit standard frames with 11-bit identifiers as well as extended frames with 29-bit identifiers. It has three transmit mailboxes, two receive FIFOs with 3 stages and 14 scalable filter banks.

3.21 Clock recovery system (CRS)

The STM32F098CC/RC/VC embeds a special block which allows automatic trimming of the internal 48 MHz oscillator to guarantee its optimal accuracy over the whole device operational range. This automatic trimming is based on the external synchronization signal, which could be either derived from LSE oscillator, from an external signal on CRS_SYNC pin or generated by user software. For faster lock-in during startup it is also possible to combine automatic trimming with manual trimming action.

3.22 Serial wire debug port (SW-DP)

An ARM SW-DP interface is provided to allow a serial wire debugging tool to be connected to the MCU.

Figure 4. LQFP100 package pinout

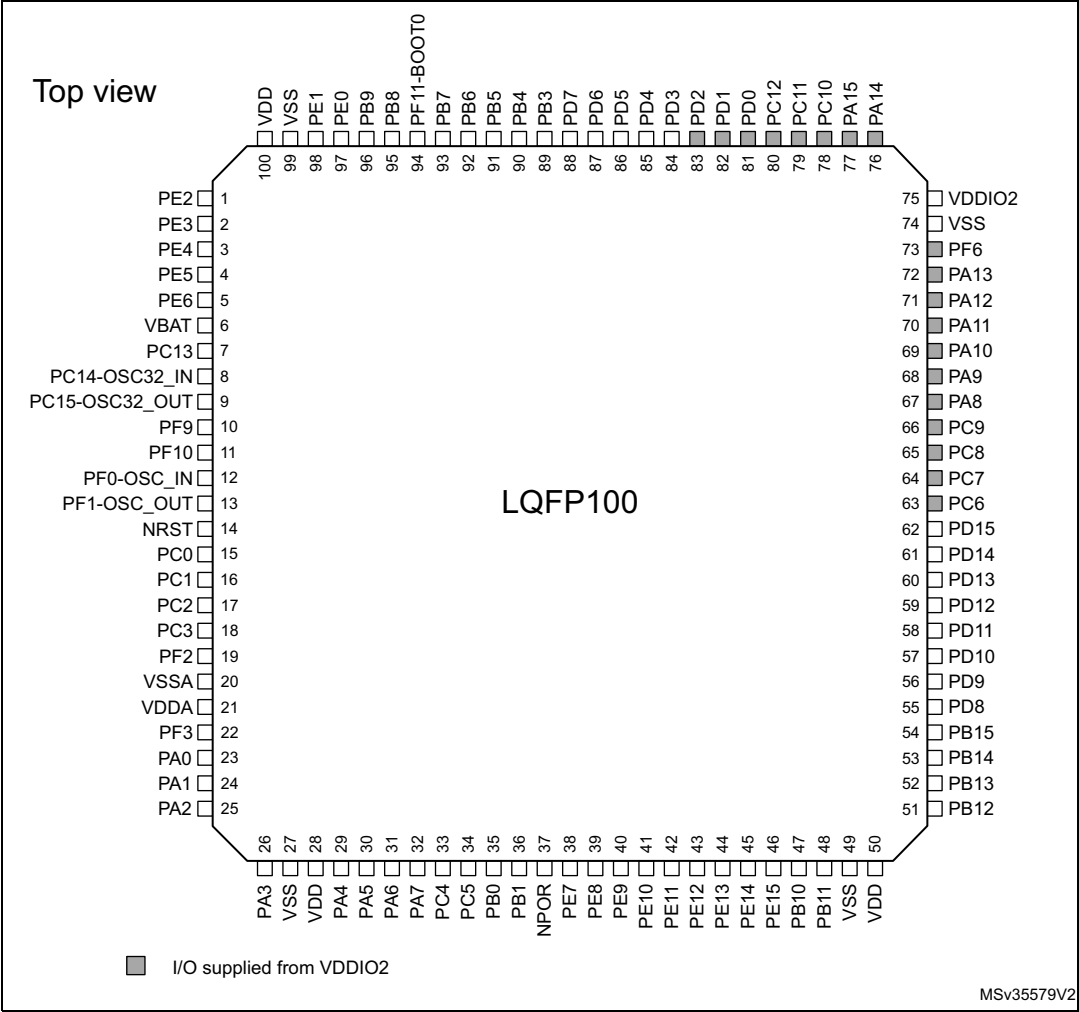


Figure 6. LQFP64 package pinout

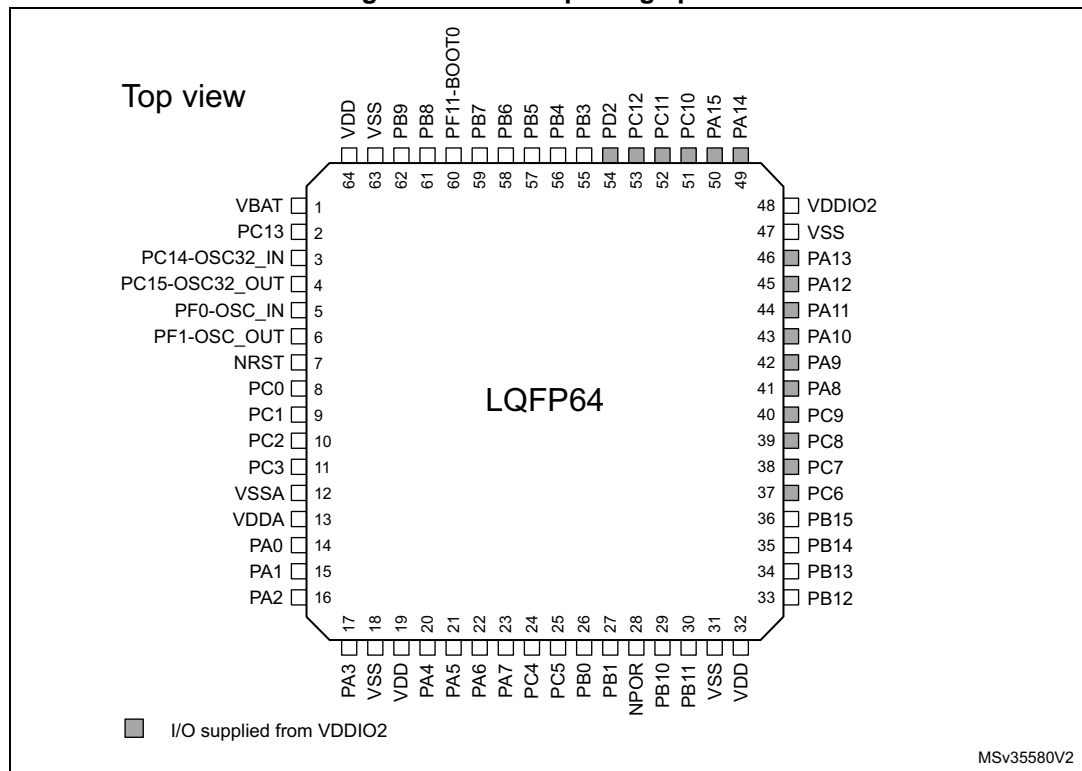


Table 12. STM32F098CC/RC/VC pin definitions (continued)

Pin numbers						Pin name (function upon reset)	Pin type	I/O structure	Notes	Pin functions	
UFBGA100	LQFP100	UFBGA64	LQFP64	WLCSP64	LQFP48/UQFPN48					Alternate functions	Additional functions
H1	15	E3	8	E7	-	PC0	I/O	TTa		EVENTOUT, USART6_TX, USART7_TX	ADC_IN10
J2	16	E2	9	F8	-	PC1	I/O	TTa		EVENTOUT, USART6_RX, USART7_RX	ADC_IN11
J3	17	F2	10	D6	-	PC2	I/O	TTa		SPI2_MISO, I2S2_MCK, EVENTOUT, USART8_TX	ADC_IN12
K2	18	G1	11	E6	-	PC3	I/O	TTa		SPI2_MOSI, I2S2_SD, EVENTOUT, USART8_RX	ADC_IN13
J1	19	-	-	-	-	PF2	I/O	FT		EVENTOUT, USART7_TX, USART7_CK_RTS	WKUP8
K1	20	F1	12	G8	8	VSSA	S	-		Analog ground	
M1	21	H1	13	H8	9	VDDA	S	-		Analog power supply	
L1	22	-	-	-	-	PF3	I/O	FT		EVENTOUT, USART7_RX, USART6_CK_RTS	
L2	23	G2	14	F7	10	PA0	I/O	TTa		USART2_CTS, TIM2_CH1_ETR, TSC_G1_IO1, USART4_TX COMP1_OUT	RTC_TAMP2, WKUP1, ADC_IN0, COMP1_INM6
M2	24	H2	15	F6	11	PA1	I/O	TTa		USART2_RTS, TIM2_CH2, TIM15_CH1N, TSC_G1_IO2, USART4_RX, EVENTOUT	ADC_IN1, COMP1_INP
K3	25	F3	16	E5	12	PA2	I/O	TTa		USART2_TX, TIM2_CH3, TIM15_CH1, TSC_G1_IO3 COMP2_OUT	ADC_IN2, WKUP4, COMP2_INM6
L3	26	G3	17	H7	13	PA3	I/O	TTa		USART2_RX, TIM2_CH4, TIM15_CH2, TSC_G1_IO4	ADC_IN3, COMP2_INP
D3	27	C2	18	G7	-	VSS	S	-		Ground	

Table 19. STM32F098CC/RC/VC peripheral register boundary addresses (continued)

Bus	Boundary address	Size	Peripheral
APB	0x4001 5C00 - 0x4001 7FFF	9 KB	Reserved
	0x4001 5800 - 0x4001 5BFF	1 KB	DBGMCU
	0x4001 4C00 - 0x4001 57FF	3 KB	Reserved
	0x4001 4800 - 0x4001 4BFF	1 KB	TIM17
	0x4001 4400 - 0x4001 47FF	1 KB	TIM16
	0x4001 4000 - 0x4001 43FF	1 KB	TIM15
	0x4001 3C00 - 0x4001 3FFF	1 KB	Reserved
	0x4001 3800 - 0x4001 3BFF	1 KB	USART1
	0x4001 3400 - 0x4001 37FF	1 KB	Reserved
	0x4001 3000 - 0x4001 33FF	1 KB	SPI1/I2S1
	0x4001 2C00 - 0x4001 2FFF	1 KB	TIM1
	0x4001 2800 - 0x4001 2BFF	1 KB	Reserved
	0x4001 2400 - 0x4001 27FF	1 KB	ADC
	0x4001 2000 - 0x4001 23FF	1 KB	Reserved
	0x4001 1C00 - 0x4001 1FFF	1 KB	USART8
	0x4001 1800 - 0x4001 1BFF	1 KB	USART7
	0x4001 1400 - 0x4001 17FF	1 KB	USART6
	0x4001 0800 - 0x4001 13FF	3 KB	Reserved
	0x4001 0400 - 0x4001 07FF	1 KB	EXTI
	0x4001 0000 - 0x4001 03FF	1 KB	SYSCFG + COMP
	0x4000 8000 - 0x4000 FFFF	32 KB	Reserved

1. Data based on characterization results, not tested in production unless otherwise specified.

Table 27. Typical and maximum current consumption in Stop mode

Symbol	Parameter	Conditions	Typ @ V _{DDA} (V _{DD} = 1.8 V)							Max			Unit
			= 1.8 V	= 2.0 V	= 2.4 V	= 2.7 V	= 3.0 V	= 3.3 V	= 3.6 V	T _A = 25 °C	T _A = 85 °C	T _A = 105 °C	
I _{DD}	Supply current in Stop mode	All oscillators OFF	0.6							2.4	33	78	μA
I _{DDA}			0.9	0.9	1.0	1.0	1.0	1.1	1.2	2.5	3.0	3.7	

Table 28. Typical and maximum current consumption from the V_{DDA} supply

Symbol	Para-meter	Conditions (1)	f _{HCLK}	V _{DDA} = 2.4 V				V _{DDA} = 3.6 V				Unit
				Typ	Max @ T _A ⁽²⁾			Typ	Max @ T _A ⁽²⁾			
					25 °C	85 °C	105 °C		25 °C	85 °C	105 °C	
I _{DDA}	Supply current in Run or Sleep mode, code executing from Flash memory or RAM	HSI48	48 MHz	311	332	337	346	315	333	340	349	μA
		HSE bypass, PLL on	48 MHz	146	167	177	180	159	180	191	196	
			32 MHz	100	118	124	126	108	126	134	137	
			24 MHz	79	95	98	99	85	100	105	108	
		HSE bypass, PLL off	8 MHz	2	3	3	4	3	3	4	4	
			1 MHz	2	2	3	3	2	3	3	4	
		HSI clock, PLL on	48 MHz	212	242	253	257	234	261	274	280	
			32 MHz	165	193	202	203	183	206	215	219	
			24 MHz	143	170	176	177	160	179	186	189	
		HSI clock, PLL off	8 MHz	64	82	84	85	76	88	91	92	

- Current consumption from the V_{DDA} supply is independent of whether the digital peripherals are enabled or disabled, being in Run or Sleep mode or executing from Flash memory or RAM. Furthermore, when the PLL is off, I_{DDA} is independent from the frequency.
- Data based on characterization results, not tested in production unless otherwise specified.

trigger circuits used to discriminate the input value. Unless this specific configuration is required by the application, this supply current consumption can be avoided by configuring these I/Os in analog mode. This is notably the case of ADC input pins which should be configured as analog inputs.

Caution: Any floating input pin can also settle to an intermediate voltage level or switch inadvertently, as a result of external electromagnetic noise. To avoid current consumption related to floating pins, they must either be configured in analog mode, or forced internally to a definite digital value. This can be done either by using pull-up/down resistors or by configuring the pins in output mode.

I/O dynamic current consumption

In addition to the internal peripheral current consumption measured previously (see [Table 32: Peripheral current consumption](#)), the I/Os used by an application also contribute to the current consumption. When an I/O pin switches, it uses the current from the I/O supply voltage to supply the I/O pin circuitry and to charge/discharge the capacitive load (internal or external) connected to the pin:

$$I_{SW} = V_{DDIOx} \times f_{SW} \times C$$

where

I_{SW} is the current sunk by a switching I/O to charge/discharge the capacitive load

V_{DDIOx} is the I/O supply voltage

f_{SW} is the I/O switching frequency

C is the total capacitance seen by the I/O pin: $C = C_{INT} + C_{EXT} + C_S$

C_S is the PCB board capacitance including the pad pin.

The test pin is configured in push-pull output mode and is toggled by software at a fixed frequency.

Table 31. Switching output I/O current consumption

Symbol	Parameter	Conditions ⁽¹⁾	I/O toggling frequency (f_{SW})	Typ	Unit
I_{SW}	I/O current consumption	$V_{DDIOX} = 1.8\text{ V}$ $C_{EXT} = 0\text{ pF}$ $C = C_{INT} + C_{EXT} + C_S$	2 MHz	0.09	mA
			4 MHz	0.17	
			8 MHz	0.34	
			18 MHz	0.79	
			36 MHz	1.50	
			48 MHz	2.06	
		$V_{DDIOX} = 1.8\text{ V}$ $C_{EXT} = 10\text{ pF}$ $C = C_{INT} + C_{EXT} + C_S$	2 MHz	0.13	
			4 MHz	0.26	
			8 MHz	0.50	
			18 MHz	1.18	
			36 MHz	2.27	
			48 MHz	3.03	
		$V_{DDIOX} = 1.8\text{ V}$ $C_{EXT} = 22\text{ pF}$ $C = C_{INT} + C_{EXT} + C_S$	2 MHz	0.18	
			4 MHz	0.36	
			8 MHz	0.69	
			18 MHz	1.60	
			36 MHz	3.27	
			48 MHz	4.35	
		$V_{DDIOX} = 1.8\text{ V}$ $C_{EXT} = 33\text{ pF}$ $C = C_{INT} + C_{EXT} + C_S$	2 MHz	0.23	
			4 MHz	0.45	
			8 MHz	0.87	
			18 MHz	2.0	
			36 MHz	3.7	
			48 MHz	4.9	
		$V_{DDIOX} = 1.8\text{ V}$ $C_{EXT} = 47\text{ pF}$ $C = C_{INT} + C_{EXT} + C_S$	2 MHz	0.29	
			4 MHz	0.55	
			8 MHz	1.09	
			18 MHz	2.43	

1. $C_S = 5\text{ pF}$ (estimated value).

On-chip peripheral current consumption

The current consumption of the on-chip peripherals is given in [Table 32](#). The MCU is placed under the following conditions:

- All I/O pins are in analog mode
- All peripherals are disabled unless otherwise mentioned
- The given value is calculated by measuring the current consumption
 - with all peripherals clocked off
 - with only one peripheral clocked on
- Ambient operating temperature and supply voltage conditions summarized in [Table 20: Voltage characteristics](#)

Table 32. Peripheral current consumption

Peripheral		Typical consumption at 25 °C	Unit
AHB	BusMatrix ⁽¹⁾	3.1	μA/MHz
	CRC	2.0	
	DMA1	5.5	
	DMA2	5.1	
	Flash memory interface	15.4	
	GPIOA	5.5	
	GPIOB	5.4	
	GPIOC	3.2	
	GIOD	3.1	
	GPIOE	4.0	
	GPIOF	2.5	
	SRAM	0.8	
	TSC	5.5	
	All AHB peripherals	61.0	

Table 49. I/O current injection susceptibility

Symbol	Description	Functional susceptibility		Unit
		Negative injection	Positive injection	
I_{INJ}	Injected current on BOOT0	-0	NA	mA
	Injected current on PF1 pin (FTf pin)	-0	NA	
	Injected current on PC0 pin (TTA pin)	-0	+5	
	Injected current on PA4, PA5 pins with induced leakage current on adjacent pins less than -20 μ A	-5	NA	
	Injected current on other FT and FTf pins, and on NPOR pin	-5	NA	
	Injected current on all other TC, TTA and RST pins	-5	+5	

6.3.13 I/O port characteristics

General input/output characteristics

Unless otherwise specified, the parameters given in [Table 50](#) are derived from tests performed under the conditions summarized in [Table 23: General operating conditions](#). All I/Os are designed as CMOS- and TTL-compliant.

Table 50. I/O static characteristics

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
V_{IL}	Low level input voltage	TC and TTA I/O	-	-	$0.3 V_{DDIOx} + 0.07^{(1)}$	V
		FT and FTf I/O	-	-	$0.475 V_{DDIOx} - 0.2^{(1)}$	
		All I/Os	-	-	$0.3 V_{DDIOx}$	
V_{IH}	High level input voltage	TC and TTA I/O	$0.445 V_{DDIOx} + 0.398^{(1)}$	-	-	V
		FT and FTf I/O	$0.5 V_{DDIOx} + 0.2^{(1)}$	-	-	
		All I/Os	$0.7 V_{DDIOx}$	-	-	
V_{hys}	Schmitt trigger hysteresis	TC and TTA I/O	-	$200^{(1)}$	-	mV
		FT and FTf I/O	-	$100^{(1)}$	-	
I_{lkg}	Input leakage current ⁽²⁾	TC, FT and FTf I/O TTa in digital mode $V_{SS} \leq V_{IN} \leq V_{DDIOx}$	-	-	± 0.1	μ A
		TTa in digital mode $V_{DDIOx} \leq V_{IN} \leq V_{DDA}$	-	-	1	
		TTa in analog mode $V_{SS} \leq V_{IN} \leq V_{DDA}$	-	-	± 0.2	
		FT and FTf I/O $V_{DDIOx} \leq V_{IN} \leq 5 V$	-	-	10	

Output driving current

The GPIOs (general purpose input/outputs) can sink or source up to +/-8 mA, and sink or source up to +/- 20 mA (with a relaxed V_{OL}/V_{OH}).

In the user application, the number of I/O pins which can drive current must be limited to respect the absolute maximum rating specified in [Section 6.2](#):

- The sum of the currents sourced by all the I/Os on V_{DDIOx} , plus the maximum consumption of the MCU sourced on V_{DD} , cannot exceed the absolute maximum rating ΣI_{VDD} (see [Table 20: Voltage characteristics](#)).
- The sum of the currents sunk by all the I/Os on V_{SS} , plus the maximum consumption of the MCU sunk on V_{SS} , cannot exceed the absolute maximum rating ΣI_{VSS} (see [Table 20: Voltage characteristics](#)).

Output voltage levels

Unless otherwise specified, the parameters given in the table below are derived from tests performed under the ambient temperature and supply voltage conditions summarized in [Table 23: General operating conditions](#). All I/Os are CMOS- and TTL-compliant (FT, TTa or TC unless otherwise specified).

Table 51. Output voltage characteristics⁽¹⁾

Symbol	Parameter	Conditions	Min	Max	Unit
V_{OL}	Output low level voltage for an I/O pin	CMOS port ⁽²⁾ $ I_{IO} = 8 \text{ mA}$ $V_{DDIOx} \geq 2.7 \text{ V}$	-	0.4	V
V_{OH}	Output high level voltage for an I/O pin		$V_{DDIOx} - 0.4$	-	
V_{OL}	Output low level voltage for an I/O pin	TTL port ⁽²⁾ $ I_{IO} = 8 \text{ mA}$ $V_{DDIOx} \geq 2.7 \text{ V}$	-	0.4	V
V_{OH}	Output high level voltage for an I/O pin		2.4	-	
$V_{OL}^{(3)}$	Output low level voltage for an I/O pin	$ I_{IO} = 20 \text{ mA}$ $V_{DDIOx} \geq 2.7 \text{ V}$	-	1.3	V
$V_{OH}^{(3)}$	Output high level voltage for an I/O pin		$V_{DDIOx} - 1.3$	-	
$V_{OL}^{(3)}$	Output low level voltage for an I/O pin	$ I_{IO} = 6 \text{ mA}$ $V_{DDIOx} \geq 2 \text{ V}$	-	0.4	V
$V_{OH}^{(3)}$	Output high level voltage for an I/O pin		$V_{DDIOx} - 0.4$	-	
$V_{OL}^{(4)}$	Output low level voltage for an I/O pin	$ I_{IO} = 4 \text{ mA}$	-	0.4	V
$V_{OH}^{(4)}$	Output high level voltage for an I/O pin		$V_{DDIOx} - 0.4$	-	V
$V_{OLFm+}^{(3)}$	Output low level voltage for an FTf I/O pin in Fm+ mode	$ I_{IO} = 20 \text{ mA}$ $V_{DDIOx} \geq 2.7 \text{ V}$	-	0.4	V
		$ I_{IO} = 10 \text{ mA}$	-	0.4	V

1. The I_{IO} current sourced or sunk by the device must always respect the absolute maximum rating specified in [Table 20: Voltage characteristics](#), and the sum of the currents sourced or sunk by all the I/Os (I/O ports and control pins) must always respect the absolute maximum ratings ΣI_{IO} .
2. TTL and CMOS outputs are compatible with JEDEC standards JESD36 and JESD52.
3. Data based on characterization results. Not tested in production.
4. Data based on characterization results. Not tested in production.

Table 54. NPOR pin characteristics

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
$V_{IL(NPOR)}$	NPOR Input low level voltage	-	-	-	$0.475 V_{DDA} - 0.2^{(1)}$	V
$V_{IH(NPOR)}$	NPOR Input high level voltage	-	$0.5 V_{DDA} + 0.2^{(1)}$	-	-	
$V_{hys(NPOR)}$	NPOR Schmitt trigger voltage hysteresis	-	-	100 ⁽¹⁾	-	mV
R_{PU}	Weak pull-up equivalent resistor ⁽²⁾	$V_{IN} = V_{SS}$	25	40	55	k Ω

1. Guaranteed by design, not tested in production.

2. The pull-up is designed with a true resistance in series with a switchable PMOS. This PMOS contribution to the series resistance is minimal (~10% order).

6.3.15 12-bit ADC characteristics

Unless otherwise specified, the parameters given in [Table 55](#) are derived from tests performed under the conditions summarized in [Table 23: General operating conditions](#).

Note: It is recommended to perform a calibration after each power-up.

Table 55. ADC characteristics

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
V_{DDA}	Analog supply voltage for ADC ON	-	2.4	-	3.6	V
$I_{DDA(ADC)}$	Current consumption of the ADC ⁽¹⁾	$V_{DDA} = 3.3\text{ V}$	-	0.9	-	mA
f_{ADC}	ADC clock frequency	-	0.6	-	14	MHz
$f_S^{(2)}$	Sampling rate	12-bit resolution	0.043	-	1	MHz
$f_{TRIG}^{(2)}$	External trigger frequency	$f_{ADC} = 14\text{ MHz}$, 12-bit resolution	-	-	823	kHz
		12-bit resolution	-	-	17	1/ f_{ADC}
V_{AIN}	Conversion voltage range	-	0	-	V_{DDA}	V
$R_{AIN}^{(2)}$	External input impedance	See Equation 1 and Table 56 for details	-	-	50	k Ω
$R_{ADC}^{(2)}$	Sampling switch resistance	-	-	-	1	k Ω
$C_{ADC}^{(2)}$	Internal sample and hold capacitor	-	-	-	8	pF
$t_{CAL}^{(2)(3)}$	Calibration time	$f_{ADC} = 14\text{ MHz}$	5.9			μs
		-	83			1/ f_{ADC}

Table 55. ADC characteristics (continued)

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
$W_{\text{LATENCY}}^{(2)(4)}$	ADC_DR register ready latency	ADC clock = HSI14	1.5 ADC cycles + 2 f_{PCLK} cycles	-	1.5 ADC cycles + 3 f_{PCLK} cycles	-
		ADC clock = PCLK/2	-	4.5	-	f_{PCLK} cycle
		ADC clock = PCLK/4	-	8.5	-	f_{PCLK} cycle
$t_{\text{latr}}^{(2)}$	Trigger conversion latency	$f_{\text{ADC}} = f_{\text{PCLK}}/2 = 14 \text{ MHz}$	0.196			μs
		$f_{\text{ADC}} = f_{\text{PCLK}}/2$	5.5			$1/f_{\text{PCLK}}$
		$f_{\text{ADC}} = f_{\text{PCLK}}/4 = 12 \text{ MHz}$	0.219			μs
		$f_{\text{ADC}} = f_{\text{PCLK}}/4$	10.5			$1/f_{\text{PCLK}}$
		$f_{\text{ADC}} = f_{\text{HSI14}} = 14 \text{ MHz}$	0.179	-	0.250	μs
$\text{Jitter}_{\text{ADC}}$	ADC jitter on trigger conversion	$f_{\text{ADC}} = f_{\text{HSI14}}$	-	1	-	$1/f_{\text{HSI14}}$
$t_{\text{S}}^{(2)}$	Sampling time	$f_{\text{ADC}} = 14 \text{ MHz}$	0.107	-	17.1	μs
		-	1.5	-	239.5	$1/f_{\text{ADC}}$
$t_{\text{STAB}}^{(2)}$	Stabilization time	-	14			$1/f_{\text{ADC}}$
$t_{\text{CONV}}^{(2)}$	Total conversion time (including sampling time)	$f_{\text{ADC}} = 14 \text{ MHz}$, 12-bit resolution	1	-	18	μs
		12-bit resolution	14 to 252 (t_{S} for sampling + 12.5 for successive approximation)			$1/f_{\text{ADC}}$

1. During conversion of the sampled value (12.5 x ADC clock period), an additional consumption of 100 μA on I_{DDA} and 60 μA on I_{DD} should be taken into account.
2. Guaranteed by design, not tested in production.
3. Specified value includes only ADC timing. It does not include the latency of the register access.
4. This parameter specify latency for transfer of the conversion result to the ADC_DR register. EOC flag is set at this time.

Equation 1: R_{AIN} max formula

$$R_{\text{AIN}} < \frac{T_{\text{S}}}{f_{\text{ADC}} \times C_{\text{ADC}} \times \ln(2^{N+2})} - R_{\text{ADC}}$$

The formula above ([Equation 1](#)) is used to determine the maximum external impedance allowed for an error below 1/4 of LSB. Here $N = 12$ (from 12-bit resolution).

Table 56. R_{AIN} max for $f_{\text{ADC}} = 14 \text{ MHz}$

T_{S} (cycles)	t_{S} (μs)	R_{AIN} max ($\text{k}\Omega$) ⁽¹⁾
1.5	0.11	0.4
7.5	0.54	5.9
13.5	0.96	11.4

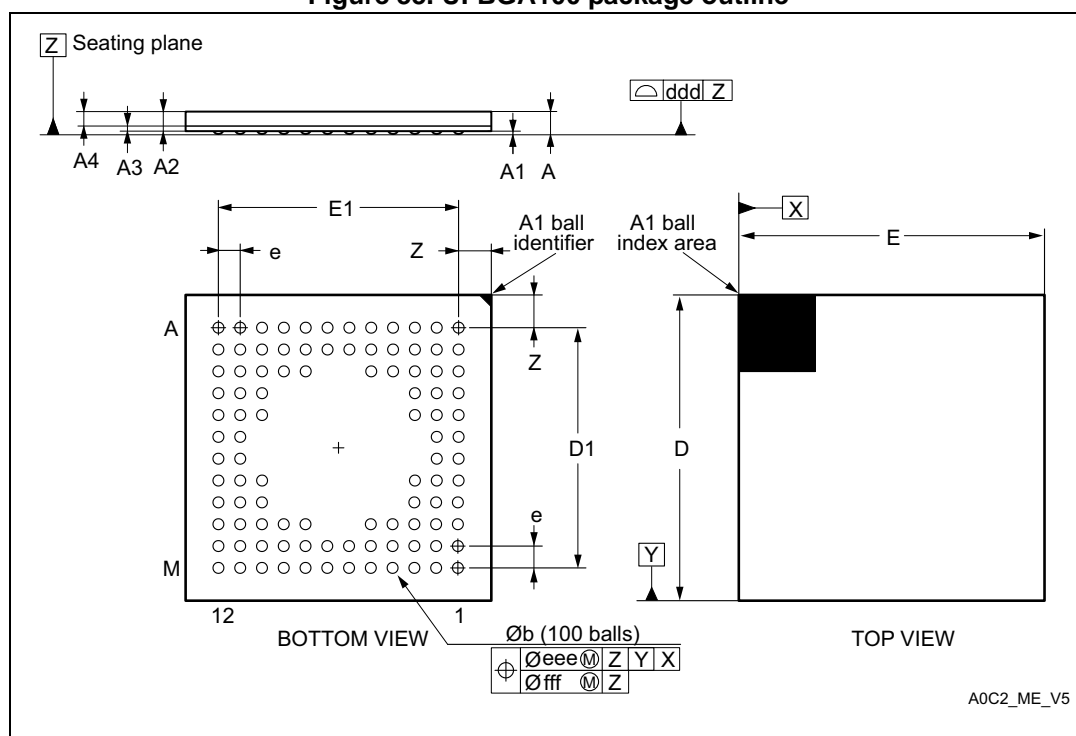
7 Package information

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: www.st.com. ECOPACK® is an ST trademark.

7.1 UFBGA100 package information

UFBGA100 is a 100-ball, 7 x 7 mm, 0.50 mm pitch, ultra-fine-profile ball grid array package.

Figure 33. UFBGA100 package outline



1. Drawing is not to scale.

Table 68. UFBGA100 package mechanical data

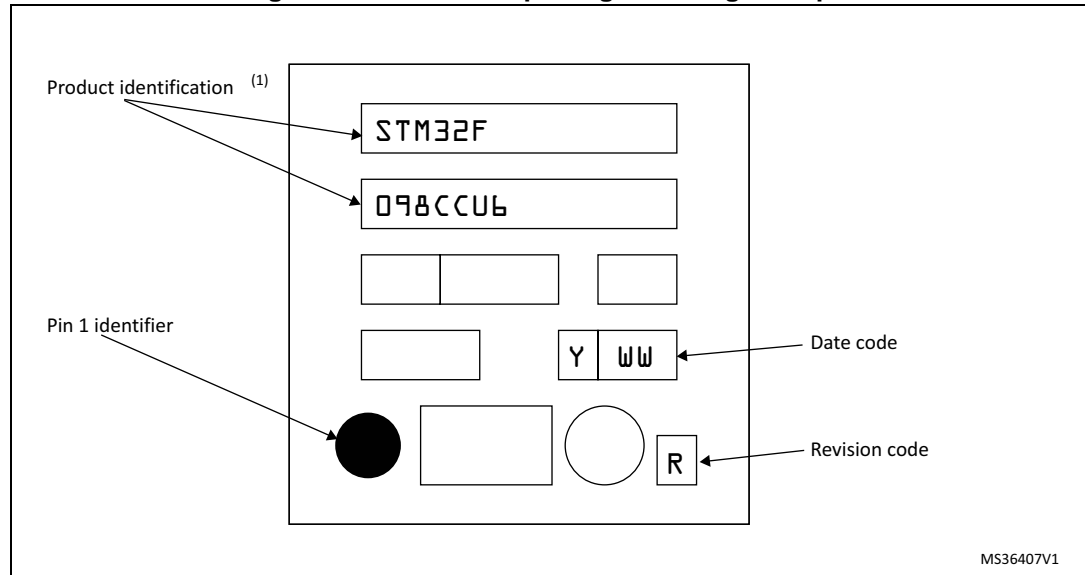
Symbol	millimeters			inches ⁽¹⁾		
	Min.	Typ.	Max.	Min.	Typ.	Max.
A	-	-	0.600	-	-	0.0236
A1	-	-	0.110	-	-	0.0043
A2	-	0.450	-	-	0.0177	-
A3	-	0.130	-	-	0.0051	0.0094
A4	-	0.320	-	-	0.0126	-

Device marking

The following figure gives an example of topside marking orientation versus pin 1 identifier location.

Other optional marking or inset/upset marks, which identify the parts throughout supply chain operations, are not indicated below.

Figure 53. UFQFPN48 package marking example



1. Parts marked as "ES", "E" or accompanied by an Engineering Sample notification letter, are not yet qualified and therefore not yet ready to be used in production and any consequences deriving from such usage will not be at ST charge. In no event, ST will be liable for any customer usage of these engineering samples in production. ST Quality has to be contacted prior to any decision to use these Engineering Samples to run qualification activity.